PATENT ASSIGNMENT

Electronic Version v1.1
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SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	ASSIGNMENT

CONVEYING PARTY DATA

Name	Execution Date
TANISYS TECHNOLOGY, INC.	09/21/2009

RECEIVING PARTY DATA

Name:	TANISYS TECHNOLOGY, INC.
Street Address:	11001 Lakeline Boulevard
Internal Address:	Building I, Suite 150
City:	Austin
State/Country:	TEXAS
Postal Code:	78717

Name:	NEOSEM, INC.
Street Address:	Samsung Techno Park, #701, 471 Wonchun-dong
Internal Address:	Yeongtong-gu, Suwon-si
City:	Gyeonggi-do
State/Country:	KOREA, DEMOCRATIC PEOPLE'S REPUBLIC OF
Postal Code:	443-824

PROPERTY NUMBERS Total: 13

Property Type	Number
Patent Number:	6285962
Patent Number:	5999468
Patent Number:	5812472
Patent Number:	5995424
Patent Number:	6182253
Patent Number:	6008664
Patent Number:	5956280
Patent Number:	6067648

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Patent Number:	6064948
Patent Number:	5914902
Patent Number:	5912852
Patent Number:	6892328
Patent Number:	6480799

CORRESPONDENCE DATA

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ATTORNEY DOCKET NUMBER:	C1309/10001
NAME OF SUBMITTER:	Scott M. Slomowitz

Total Attachments: 3
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ASSIGNMENT

WHEREAS, TANISYS TECHNOLOGY, INC., a corporation organized and existing under the laws of the State of Wyoming, and having an address at 11001 Lakeline Blvd., Bldg. I, Suite 150, Austin, Texas 78717 (hereinafter "TANISYS") has acquired, by assignment, all right, title, and interest in and to the issued patents and the inventions which form the subject matter of the issued patents identified in EXHIBIT A, attached hereto, all of said issued patents and the inventions which form the subject matter of said issued patents hereinafter being collectively referred to as "PATENT RIGHTS";

WHEREAS, NEOSEM, INC., a Republic of Korea corporation having a place of business at Samsung Techno Park #701, 471 Wonchun-dong, Yeongtong-gu, Suwon-si, Gyeonggi-do 443-824, Republic of Korea (hereinafter "NEOSEM"), previously entered into a DEVELOPMENT AND LICENSE AGREEMENT (hereinafter "AGREEMENT"), dated June 1, 2009, with TANISYS;

WHEREAS, pursuant to said AGREEMENT, TANISYS and NEOSEM are joint owners of said PATENT RIGHTS;

WHEREAS, TANISYS wishes to further memorialize the joint ownership of the PATENT RIGHTS by TANISYS and NEOSEM in a form suitable for recording at the United States Patent and Trademark Office;

NOW, THEREFORE, TANISYS, intending to be legally bound, and for good and valuable consideration set forth in the AGREEMENT, the receipt and sufficiency of which is hereby acknowledged, agrees as follows:

TANISYS hereby confirms the AGREEMENT that the PATENT RIGHTS are to be jointly owned by TANISYS and NEOSEM, confirms that as of June 1, 2009, the PATENT RIGHTS were jointly owned by TANISYS and NEOSEM and does hereby sell, assign and transfer to NEOSEM a 50% ownership in and to TANISYS's entire right, title and interest in the PATENT RIGHTS.

IN WITNESS WHEREOF, I hereunto affix my hand and seal this 21 day of Sep., 2009.

TANISYS TECHNOLOGY, INC.

By: ______________________
Name: Dong Hyun YEOM
Title: CEO, President

____
WITNESS
Name: Scott Simpson
Address: 11001 Lakeline Blvd
Austin TX 78717

정홍진
WITNESS
Name: Hong Jin, Jung
Address: Samsung Techno Park #101,
471 Wonchun-Dong, Suwon-Si

EXHIBIT A

U.S. Patent No.	Title	Issue Date
6,285,962	Method & System for Testing Rambus Memory Modules	Sep. 4, 2001
5,999,468	Method & System for Identifying a Memory Module Configuration	Dec. 7,1999
5,812,472	Nested Loop Method of Identifying Synchronous Memories	Sep. 22, 1998
5,995,424	Synchronous Memory Test System	Nov. 30, 1999
6,182,253	Method & System for Automatic Synchronous Memory Identification	Jan. 30, 2001
6,008,664	Parametric Test System & Method	Dec. 28, 1999
5,956,280	Contact Test Method & System for Memory Testers	Sep. 21, 1999
6,067,648	Programmable Pulse Generator	May 23, 2000
6,064,948	Tester Systems	May 16, 2000
5,914,902	Synchronous Memory Tester	Jun. 22, 1999
5,912,852	Synchronous Memory Test Method	Jun. 15, 1999
6,892,328	Method & System for Distributed Testing of Electronic Devices	May 10, 2005
6,480,799	Method & System for Testing RAMBUS Memory Modules	Nov. 12, 2002